

<b>Notice of References Cited</b>	Application/Control No. 10/572,607	Applicant(s)/Patent Under Reexamination GEIER ET AL.	
	Examiner LEE D. WILSON	Art Unit 3723	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,474,632 B1	11-2002	Liou, Ferng-Jong	269/6
*	B	US-6,564,703 B1	05-2003	Lin, Kun-Meng	100/234
*	C	US-2004/0075205 A1	04-2004	Marks, Joel	269/006
*	D	US-6,966,550 B2	11-2005	Marks, Joel	269/6
*	E	US-2007/0194510 A1	08-2007	Geler et al.	269/006
*	F	US-7,322,085 B1	01-2008	Benson, Joel Kent	29/237
*	G	US-2008/0029944 A1	02-2008	AVALANI, BIANCA R. RAY	269/006
*	H	US-2008/0136077 A1	06-2008	Yang, Ching-chen	269/6
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.